

Description

The invention relates to an apparatus for optically scanning a radiation-reflective information plane, which apparatus comprises a diode laser supplying a scanning beam, an objective system for focussing the scanning beam to form a scanning spot in the information plane and for re-imaging the scanning spot on a composite radiation-sensitive detection system, and a composite diffraction element which is arranged in the radiation path between the diode laser and the objective system for deflecting the radiation beam reflected by the information surface to the radiation-sensitive detection system and for splitting said beam into a plurality of sub-beams forming a corresponding plurality of radiation spots on a corresponding plurality of detector pairs of the composite detection system.

An apparatus of this type, which is in principle suitable for reading a pre-recorded optical record carrier and for optically recording such a record carrier, is known from United States Patent No. 4,665,310 (PHN 11.531). In this apparatus the composite diffraction element in the form of a diffraction grating performs two functions for which otherwise two separate elements are required. Firstly the grating ensures that the radiation which has been reflected by the information surface and which traverses the objective system is deflected from the path of the radiation emitted by the diode laser, so that a detection system can be arranged in the path of the reflected radiation. Secondly, the grating splits the reflected beam into two sub-beams required for generating a focussing error signal, i.e. a signal containing information about the magnitude and the direction of a deviation between the focal plane of the objective system and the information plane. Each of the sub-beams is associated with a separate detector pair, the signal representing the difference between the output signals of the detectors of the same pair being a measure of the focussing of the scanning beam on the information plane.

In the said record carrier the information is arranged in accordance with information tracks. If the bounding line between the two sub-gratings extends parallel to the track direction, it is possible, by determining the sum of the output signals of each detector pair and subtracting these sum signals from each other, to form a signal containing information about the magnitude and the direction of a deviation between the centre of the scanning spot and the central axis of the information track to be scanned.

In order to obtain the desired beam-splitting, the diffraction grating in the known apparatus comprises two sub-gratings having the same grating

period, whilst the grating strips of the first sub-grating extend at a first angle and the grating strips of the second sub-grating extend at a second angle, which is equal but opposite to the first angle, to the line separating the two sub-gratings. Since a diffraction grating deflects an incident beam in a plane transversely to the direction of the grating lines, the part of the beam which is incident on one of the sub-gratings will be given a different direction than the part of the beam which is incident on the second sub-grating.

As set forth in United States Patent No. 4,665,310 the grating design described in this patent is based on a previously proposed composite diffraction grating. This grating comprises two sub-gratings in which the grating strips of the one sub-grating have the same direction as those of the other sub-grating, but in which the grating periods of the two sub-gratings are different. Since the angle at which an incident beam is deflected by a grating depends on the grating period, the part of the beam incident on one of the sub-gratings is deflected at an angle which is different from the angle at which the part of the beam which is incident on the other sub-grating is deflected.

Satisfactory experience has been gained with scanning apparatus provided with these gratings. However, it has been found that when using a grating a deviation in the generated focussing error signal may occur which, it is true, remains within the range of tolerance laid down for this signal, but leaves only little room for possible other deviations. The last-mentioned deviations may be caused by mutual movements of the optical components, and by varying settings in the electronic processing circuit.

As is known the wavelength λ of the radiation beams emitted by diode lasers which are frequently used in practice may vary, for example due to temperature variations. The wavelengths of individual diode lasers, which have been manufactured by means of the same process at different points of time, may also mutually differ. A wavelength variation of the scanning beam results in a variation of the angles at which the sub-beams are deflected by the sub-gratings, resulting in a change of the positions of the radiation spots on the detector pairs.

To prevent these position changes from affecting the generated focussing error signal, it has already been proposed to arrange the separating strips of each detector pair in such a way that the displacement of the radiation spots due to the wavelength variations occurs along these separating strips. However, the varying intensity distribution of these radiation spots has not been taken into account.

When correctly focussing the scanning beam on the information plane and in the case of the correct, or nominal wavelength of this beam, the sub-beams from the diffraction grating form radiation spots on their associated detector pairs, which spots have intensity distributions which are symmetrical with respect to these detector pairs. When varying the wavelength of the scanning beam, not only the positions of these radiation spots change but these spots also become asymmetrically larger in the direction transversely to the separating strips because the focussing of the sub-beams with respect to the associated detector pairs changes, even in the case of a constant and correct focussing of the scanning beam on the information plane. Then the fact that each sub-beam originates from a grating covering only half the exit pupil of the objective system, so that these sub-beams are asymmetrical, starts to play a role. The magnification of a radiation spot occurring as a result of the wavelength variation is asymmetrical, so that the centre of the intensity distribution of a radiation spot performs a movement with a movement component transversely to the separating strip of the associated detector pair. In the case of a wavelength signal of the detectors associated with a pair, which change is interpreted by the focus servo-system as a focussing error of the scanning beam with respect to the information plane. The focus servo-system then starts to "correct" in such a way that the scanning spot is no longer focussed on the information plane in an optimum manner.

The invention has for its object to provide a solution to this novel problem. The apparatus according to the invention is characterized in that for each detector pair the separating strip between the two detectors extends at an acute angle to the line connecting the centre of the radiation emitting surface of the diode laser with the position assumed by the centre of the intensity distribution of the radiation spot formed on the relevant detector pair if the scanning beam is focussed on the information plane in an optimum manner.

The separating strip of each detector pair is then located in such a manner that the displacement of the centre of the intensity distribution of the associated radiation spot, which results from the wavelength variation, is effected along this separating strip, so that this displacement does not result in a change of the intensity distribution over the detectors and therefore has no influence on the focussing error signal.

The invention can be used in scanning apparatus in which the diffraction element is constituted by a grating composed of a plurality of sub-gratings.

The sub-gratings may comprise straight grating strips and they may have a constant grating period.

However, the apparatus is preferably characterized in that the sub-gratings have a varying grating period and in that the grating strips are curved.

When using a diffraction grating having a varying grating period, less stringent requirements need to be imposed on the mutual position accuracy of the diode laser and the detectors in the form of photodiodes, which is particularly important if the height, measured along the optical axis of the objective system, of the apparatus must be reduced. In addition, when using gratings having curved grating strips, it is possible by adapting the curvatures during manufacture of the composite grating, to correct for imaging errors such as coma and astigmatism, which may occur when using a diffraction grating having straight grating strips.

A first embodiment of an apparatus in which the composite grating comprises two sub-gratings and in which the grating strips of the one sub-grating have the same direction as those of the other sub-grating and the grating periods of the sub-gratings are different, and in which the detector pairs are juxtaposed in a direction parallel to the separating line between the sub-gratings is characterized in that the separating strips of the detector pairs extend at opposite angles to the same connection line.

A second embodiment of an apparatus using two sub-gratings having the same grating period, whilst the grating strips of the first sub-grating extend at a first angle and the grating strips of the second sub-grating extend at a second angle, which is equal but opposite to the first angle, to the separating line of the two sub-gratings, and in which the detector pairs are juxtaposed in a direction transversely to the direction of the said separating line is characterized in that the separating strips of the detector pairs extend at equally large but opposite angles to the said connection line.

The invention will now be described in greater detail by way of example with reference to the accompanying drawings in which

Figure 1 shows diagrammatically an embodiment of a read apparatus with a diffraction grating,

Figure 2 is a perspective diagrammatical view of a first embodiment of the diffraction grating and the associated detection system,

Figures 3a and 3b show the variations of the radiation spots on the detectors upon the occurrence of focussing errors

Figures 4a, 4b, 4c show the variations of the sub-beams upon the occurrence of a wavelength variation of the scanning beam,

Figure 5 shows the changes, introduced by these variations, of a radiation spot formed on a

photodiode pair,

Figure 6 shows the radiation-sensitive detection system according to the invention, associated with the first embodiment of the diffraction grating,

Figure 7 shows a second embodiment of the diffraction grating and the associated radiation-sensitive detection system,

Figures 8a and 8b show the variations of the radiation spots on the photodiodes upon the occurrence of focussing errors,

Figure 9 shows the variations of a radiation spot formed on a photodiode pair due to a variation of the wavelength of the scanning beam and

Figure 10 shows the radiation-sensitive detection system according to the invention, associated with the second embodiment of the diffraction grating.

Figure 1 is a tangential cross-sectional view of a small part of an optical record carrier 1 having a radiation-reflecting information plane 2. This Figure shows one of the tracks 3 situated in the information plane 2. Such a track comprises information areas 3a alternating with intermediate areas 3b, whilst, for example the areas 3a are located at a height differing from that of the intermediate areas 3b. The information surface is scanned by a beam b emitted by a diode laser 4. This beam is focussed by an objective system 6 diagrammatically represented by a single lens, to form a tiny scanning spot V in the information plane. A separate collimator lens may be arranged ahead of the objective system. The imaging system may be alternatively formed by a combined collimator-objective system as is shown in Figure 1. As the record carrier is rotated about an axis 8, which is parallel to the optical axis 00', a track 3 is scanned and the read beam is modulated by the information contained in this track. By moving the record carrier and the read unit comprising the source 4, the objective system 6 and the detection system 10 in a radial direction relative to one another, the entire information surface is scanned.

The beam which has been reflected and modulated by the information surface should be detected, which means that this beam should be separated from the beam emitted by the source 4. Therefore the apparatus should comprise a beam-separating element.

For reading an information structure with minute information details, for example of the order of 1 μm , an objective system having a large numerical aperture is required. The depth of focus of such an objective system is small. Since variations in the distance between the information plane 2 and the objective system 6 may occur which are larger than the depth of focus, steps have to be taken in order to detect these variations and, in

response thereto, correct the focussing. To this end the apparatus may be provided with a beam splitter which splits the reflected beam into two sub-beams, and with, for example, two detector pairs of which a first pair co-operates with the first sub-beam and the second pair co-operates with the second sub-beam. The output signals of the detectors are processed to form, *inter alia*, a focus servo-signal.

As described in the Article "Optische Fokusfehlerdetektion" in "Neues aus der Technik", No. 6, 15 December 1980, page 3, beam separation and beam splitting can be effected by means of a single element, namely a transparent grating. This grating splits the beam which is reflected by the information surface 2 and which traverses the objective system 6 into a non-deflected zero-order sub-beam and a plurality of first-order and higher-order sub-beams. The grating parameters, specifically the ratio between the width of the grating strips and that of the intermediate strips and the depth and the shape of the grating grooves may be selected in such a way that a maximum quantity of radiation is incident on the detection system.

Figure 2 is a perspective elevational view of a first embodiment of the grating 9 and the radiation-sensitive detection system 10. The beam b is indicated by its cross-section at the area of the grating. The grating 9 comprises two sub-gratings 12 and 13 separated from each other by the line 11. The grating strips of the sub-gratings 12 and 13 are denoted by 14 and 15, respectively. These grating strips are separated by intermediate strips 16 and 17. In this embodiment the grating strips at the area of the separating line 11 have the same direction and are, for example perpendicular to the bounding line. The average grating period p_1 of the sub-grating 12 is, however, different from the average grating period p_2 of the sub-grating 13. Consequently, the angle at which the sub-beam b_2 is deflected differs from the angle at which the sub-beam b_1 is deflected. This means that in the plane of the detectors the radiation spots V_1 and V_2 are offset with respect to each other in the Y direction.

Radiation-sensitive detectors in the form of photodiodes 18, 19 and 20, 21 which are separated by narrow strips 22 and 23, respectively, are associated with each of the sub-beams b_1 and b_2 . These detectors are positioned in such a way that in the case of a correct focussing of the beam b on the information surface 2 the intensity distribution of the radiation spots V_1 and V_2 formed by the sub beams b_1 and b_2 is symmetrical relative to the detectors 18, 19 and 20, 21, respectively. When a focussing error occurs, the radiation spots V_1 and V_2 become asymmetrically broader as is shown in Figures 3a and 3b. Figure 3a shows the situation in which the beam b is focussed in a plane in front of

the information surface 2, whereas Figure 3b relates to the situation in which the beam b is focussed in a plane behind the information surface.

If the output signals of the detectors 18, 19, 20 and 21 are represented by S_{18} , S_{19} , S_{20} and S_{21} , respectively, the focussing error signal will be given by

$$S_f = (S_{18} + S_{21}) - (S_{19} + S_{20})$$

A signal which is proportional to the information being read, or the information signal S_i is given by:

$$S_i = S_{18} + S_{19} + S_{20} + S_{21}$$

If the bounding line 11 of the two sub-gratings 12 and 13 extends parallel to the direction of a track 3 being read, it is also possible to generate a tracking error signal S_r from the detector signals. This signal is given by:

$$S_r = (S_{18} + S_{19}) - (S_{20} + S_{21})$$

The apparatus can be dimensioned and the geometry of the composite grating and the wavelength of the scanning beam can be adapted to each other in such a way that, if the plane in which the scanning beam b is focussed coincides with the information plane 2, the sub-beams b_1 and b_2 are focussed on the separating strips of the photodiode pairs 18, 19, 20 and 21. Then the size of the radiation spots V_1 and V_2 is minimum and the intensity distribution of each spot is symmetrical with respect to the associated detector pair.

When varying the wavelength of the scanning beam, the angles at which the sub-beams are deflected by the sub-gratings will vary. For each sub-beam this means not only that the position where the chief ray of this sub-beam is incident on the associated photodiode pair is displaced, but also that this sub-beam is focussed in a plane which is located below or above the radiation sensitive surface of the photodiode pair.

This is illustrated in Figures 4a, 4b and 4c for the sub-beam b_1 . An analogous effect occurs for the sub-beam b_2 . In these Figures the reference numeral 9 again denotes the composite grating, the reference numeral 4 denotes the diode laser and the reference numeral 10 denotes the surface of the composite photodiode. Figure 4a shows the situation in which the wavelength has the correct, or nominal value. In the situation shown in Figure 4b the wavelength is smaller than the nominal value and the sub-beam is focussed in a plane below the radiation-sensitive surface 10 of the photodiodes. If the wavelength is larger than the nominal value, the sub-beam is focussed in a plane above the radiation-sensitive surface of the

photodiodes, as is shown in Figure 4c. A defocussing of the sub-beam b_1 does not only result in the radiation spot V_1 formed on the radiation sensitive surface of the photodiodes becoming bigger but also in this spot acquiring an asymmetrical shape. In fact, the sub-beam b_1 originates from the sub-grating 12 located in Figure 2 above the separating line 11. This separating line bisects the exit pupil of the objective system 6 and hence also the scanning beam b reflected by the information surface 2 so that the cross-section of the sub-beam b_1 is semi-circular. The radiation spot V_1 is therefore not round and upon defocussing of the sub-beam b_1 this spot has an approximately semi-circular shape.

Figure 5 illustrates how the position, the shape and the size of the radiation spot V_1 change when the wavelength of the scanning beam is varied. It has been assumed that this beam is sharply focussed on the information plane. $V_{1,0}$ is the radiation spot which is formed if the wavelength has the nominal value and if the sub-beam b_1 is sharply focussed on the radiation-sensitive surface of the detectors 18 and 19. When increasing the wavelength, the radiation spot moves to the right and this spot becomes bigger and bigger, which is indicated by the spots $V_{1,1}$, $V_{1,2}$. If the wavelength becomes smaller than the nominal value, the radiation spot moves to the left and this spot also becomes bigger and bigger, which is indicated by the spots $V_{1,3}$ and $V_{1,4}$. The centres of the intensity distribution of the spots $V_{1,0}$, $V_{1,1}$, $V_{1,2}$, $V_{1,3}$ and $V_{1,4}$ are denoted by $M_{1,0}$, $M_{1,1}$, $M_{1,2}$, $M_{1,3}$ and $M_{1,4}$. These centres are located on a line 22' which extends at a small angle α_1 of the order of several degrees to the original separating strip 22 of the detectors 18 and 19. An analogous effect occurs for the radiation spot V_2 , with the line along which the centre of the intensity distribution is displaced extending at an angle to the separating strip 23, which angle is opposite to and has a different value than the angle α_1 .

The result of a wavelength variation thus is that the centre of the intensity distribution of the radiation spots V_1 and V_2 , is displaced transversely to the separating strips 22 and 23, respectively, and hence the detectors 18, 19 and 20, 21, respectively, receive different radiation intensities. The output signals of the detectors 18, 19 and 20, 21 are then no longer equal whilst nevertheless the scanning beam is sharply focussed on the information plane. The focus servo-system then starts to correct the focussing of the scanning beam, for example, by moving the objective system along the optical axis until these output signals are equal again. Then, however, the scanning beam is no longer nominally focussed on the information plane.,

It has been found that in a given embodiment of the apparatus a wavelength variation of 20 nm at a nominal wavelength of 785 nm caused a defocussing of the order of 0.7 to 0.8 μm , whilst the permitted total focussing error is, for example, 1 μm .

In order to eliminate the influence of wavelength variations on the focussing error signal to a substantial extent, the invention ensures that the separating strip for each photodiode pair is located in such a way that the displacement of the centre of the intensity distribution of the associated radiation spot is effected along this strip. In Figure 6 photodiode pairs modified in accordance with the invention are denoted by 18, 19 and 20, 21, respectively. The new separating strips are shown by means of the solid lines 22' and 23'. As compared with the original strips 22 and 23 shown by means of broken lines, the strips 22' and 23' are rotated about the points $M_{1,0}$ and $M_{2,0}$ through small angles α_1 and α_2 , respectively.

Figure 7 diagrammatically shows a second embodiment of the composite diffraction grating and the associated photodiode configuration. The sub-gratings now have the same grating period but the main directions of the curved grating strips 14 of the sub-grating 12 extend at a first angle to the separating line 11, whilst the main directions of the curved grating strips 15 of the second sub-grating 13 extend at a second, preferably equally large but opposite angle to the separating line. The sub-beams are mainly deflected in a direction transversely to the main directions, so that the photodiodes must be arranged differently than in Figure 2. The bounding strips 22 and 23 of the detector pairs in the XY-plane are now located one after the other in the X-direction. The focussing error signal, the information signal and the tracking error signal are obtained in the same way as described with reference to Figure 2.

Since the efficiency of a diffraction grating, i.e. the quotient of the quantity of radiation deflected in the desired direction and the total quantity of radiation incident on the grating depends on, *inter alia* the grating period, the composite diffraction grating shown in Figure 7 is preferred to that shown in Figure 2. In fact, due to the unequal grating periods of the sub-gratings in the last-mentioned grating the sub-beams may acquire unequal intensities so that an offset in the tracking error signal may be produced. This type of offset cannot occur in an apparatus comprising the diffraction grating as shown in Figure 7.

In Figures 8a and 8b showing the photodiode pairs according to Figure 7 in a plan view, it has been illustrated how the radiation spots V_1 and V_2 are located with respect to the separating strips 22 and 23. In the case of a correct focussing of the

scanning beam on the information plane and of the sub-beams on the detector surface the radiation spots V_1 and V_2 are minimal and are located on the separating strips 22 and 23. Figure 8a shows the radiation spots V_1' and V_2' which are produced if the scanning beam is focussed in a plane in front of the information surface, whilst Figure 8b shows the radiation spots V_1'' and V_2'' which are produced if the scanning beam is focussed in a plane behind the information surface.

Analogously as in Figure 5, Figure 9 shows how the position, the shape and the size of the radiation spot V_1 change when varying the wavelength of the scanning beam. Figure 9 does not require any further explanation after the description of Figure 5.

Figure 10 shows the photodiode pairs 18, 19 and 20, 21 used in the arrangement of Figure 7 and modified in accordance with the invention. With respect to the original strips 22 and 23, the new separating strips 22' and 23' are rotated through a small angle β about the points $M_{1,0}$ and $M_{2,0}$, the centres of the intensity distributions of the radiation spots V_1 and V_2 in the case of correct focussing of the scanning beam on the information plane and in the case of the nominal wavelength. It is to be noted that the sign of the angle β is determined by the geometry of the apparatus, notably the mutual positions of the diode laser and the grating and those of the diode laser and the detectors. It is alternatively possible for the lines 22' and 23' to be turned counterclockwise and clockwise with respect to the lines 22 and 23, respectively, instead of clockwise and counterclockwise, respectively as in Figure 10.

The invention may be used in any focussing error detection system in which a diffraction element is used for separating the beam reflected by the information plane and the beam emitted by the diode laser and for splitting the reflected beam into a plurality of sub-beams. In practice, two sub-beams are generally used which are formed by means of two sub-gratings. Under circumstances it may be desirable to use a composite grating having more than two sub-gratings, so that more than two sub-beams are formed. The measure according to the invention may be taken for each detector pair associated with these sub-beams. The sub-gratings may have straight grating lines and a constant grating period. However, a type of grating, also referred to as holograms, whose embodiments are shown in Figures 2 and 7 is preferably used. The sub-gratings in these embodiments have a varying grating period, with the variation in the period being, for example, of the order of several percent of the average grating period. Besides, as is shown in Figures 2 and 7, the grating strips of the two sub-gratings are curved. Thus, these sub-

gratings have a variable lens action. Due to the varying grating period the positions of the radiation spots V_1 and V_2 can be varied by displacing the grating 9 in its own plane. Aberrations in a direction perpendicular to the direction of the separating line 11 may be minimized by the curvatures of the grating strips. The possibility of displacing the positions of the radiation spots V_1 and V_2 is particularly important if an integrated laser-photodiode unit is used, i.e. a component in which the diode laser and the photodiodes are arranged on one support and are therefore fixed with respect to each other and thus have a fixed mutual distance in the Z-direction. This distance is subject to manufacturing tolerances and cannot be corrected during assembly of the apparatus by displacing the photodiodes with respect to the laser diode in the Z-direction.

Also the distance in the Y-direction between the diode laser and the centres of the detector pairs is subject to manufacturing tolerances. A compensation therefor can also be obtained by displacing the grating 9 in the direction of the line 11.

In the embodiment according to Figure 2 it can be ensured that, in spite of the different angles at which the sub-beams b_1 and b_2 are deflected in the YZ-plane due to the different average grating periods of the sub-gratings 12 and 13, the foci of the sub-beams are in one XY-plane, namely by giving the grating periods and the curvatures of the grating strips of corresponding parts of the sub-gratings a different variation.

An important advantage of the diffraction grating having curved grating strips as compared with a grating having straight grating strips is that the optical aberrations such as coma and astigmatism, which may occur when using the last-mentioned grating, can be avoided in the first-mentioned grating by taking these aberrations into account in the manufacture of this grating and by adapting the curvatures of the grating strips thereto.

The invention has been described for use in a read apparatus, but it may alternatively be used in a write apparatus or in a combined write/read apparatus in which during recording the focussing and the tracking of the write beam are monitored. The focussing error detection system described does not utilize special properties of the information surface 2. It is merely necessary and adequate that this surface is reflecting. Therefore the invention may be used in various apparatus where very accurate focussing is required, for example in microscopes, in which case the tracking error detection may be dispensed with.

Claims

1. An apparatus for optically scanning a radiation-reflective information plane (2), which apparatus comprises a diode laser (4) supplying a scanning beam (b), an objective system (6) for focussing the scanning beam to form a scanning spot (V) in the information plane and for re-imaging the scanning spot on a composite radiation-sensitive detection system (10), and a composite diffraction element (9) which is arranged in the radiation path between the diode laser and the objective system for deflecting the radiation beam reflected by the information surface to the radiation-sensitive detection system and for splitting said beam into a plurality of sub-beams (b_1, b_2) forming a corresponding plurality of radiation spots (V_1, V_2) on a corresponding plurality of detector pairs (18,19;20,21) of the composite detection system (10), characterized in that for each detector pair (18,19;20,21) the separating strip (22',23') between the two detectors extends at an acute angle ($\alpha_1, \alpha_2, \beta$) to the line connecting the centre of the radiation-emitting surface of the diode laser (4) with the position ($M_{1,0}, M_{2,0}$) assumed by the centre of the intensity distribution of the radiation spot (V_1, V_2) formed on the relevant detector pair (18,19;20,21) if the scanning beam (b) is focussed on the information plane (2) in an optimum manner.
2. An apparatus as claimed in Claim 1, in which the composite diffraction element (9) is constituted by two subgratings (12, 13) characterized in that the sub-gratings (12,13) have a varying grating period (P_1, P_2) and in that the grating strips (14,16;15,17) are curved.
3. An apparatus as claimed in Claim 1 or 2 in which the diffraction element (9) is constituted by two sub-gratings (12,13) in which the grating strips (14,16) of the one sub-grating (12) have the same direction as those (15,17) of the other sub-grating (13) and the periods (P_1, P_2) of the sub-gratings are different, and in which the detector pairs (18,19;20,21) are juxtaposed in a direction parallel to the separating line (11) between the sub-gratings (12, 13), characterized in that the separating strips (22', 23') of the detector pairs extend at opposite angles (α_1, α_2) to the said connection line.
4. An apparatus as claimed in Claim 1 or 2 in which the diffraction element (9) is constituted by two sub-gratings (12, 13) which have the same grating period, whilst the grating strips (14,16) of the first sub-grating (12) extend at a



gratings have a variable lens action. Due to the varying grating period the positions of the radiation spots V_1 and V_2 can be varied by displacing the grating 9 in its own plane. Aberrations in a direction perpendicular to the direction of the separating line 11 may be minimized by the curvatures of the grating strips. The possibility of displacing the positions of the radiation spots V_1 and V_2 is particularly important if an integrated laser-photodiode unit is used, i.e. a component in which the diode laser and the photodiodes are arranged on one support and are therefore fixed with respect to each other and thus have a fixed mutual distance in the Z-direction. This distance is subject to manufacturing tolerances and cannot be corrected during assembly of the apparatus by displacing the photodiodes with respect to the laser diode in the Z-direction.

Also the distance in the Y-direction between the diode laser and the centres of the detector pairs is subject to manufacturing tolerances. A compensation therefor can also be obtained by displacing the grating 9 in the direction of the line 11.

In the embodiment according to Figure 2 it can be ensured that, in spite of the different angles at which the sub-beams b_1 and b_2 are deflected in the YZ-plane due to the different average grating periods of the sub-gratings 12 and 13, the foci of the sub-beams are in one XY-plane, namely by giving the grating periods and the curvatures of the grating strips of corresponding parts of the sub-gratings a different variation.

An important advantage of the diffraction grating having curved grating strips as compared with a grating having straight grating strips is that the optical aberrations such as coma and astigmatism, which may occur when using the last-mentioned grating, can be avoided in the first-mentioned grating by taking these aberrations into account in the manufacture of this grating and by adapting the curvatures of the grating strips thereto.

The invention has been described for use in a read apparatus, but it may alternatively be used in a write apparatus or in a combined write/read apparatus in which during recording the focussing and the tracking of the write beam are monitored. The focussing error detection system described does not utilize special properties of the information surface 2. It is merely necessary and adequate that this surface is reflecting. Therefore the invention may be used in various apparatus where very accurate focussing is required, for example in microscopes, in which case the tracking error detection may be dispensed with.

Claims

1. An apparatus for optically scanning a radiation-reflective information plane (2), which apparatus comprises a diode laser (4) supplying a scanning beam (b), an objective system (6) for focussing the scanning beam to form a scanning spot (V) in the information plane and for re-imaging the scanning spot on a composite radiation-sensitive detection system (10), and a composite diffraction element (9) which is arranged in the radiation path between the diode laser and the objective system for deflecting the radiation beam reflected by the information surface to the radiation-sensitive detection system and for splitting said beam into a plurality of sub-beams (b_1, b_2) forming a corresponding plurality of radiation spots (V_1, V_2) on a corresponding plurality of detector pairs (18,19;20,21) of the composite detection system (10), characterized in that for each detector pair (18,19;20,21) the separating strip (22',23') between the two detectors extends at an acute angle ($\alpha_1, \alpha_2, \beta$) to the line connecting the centre of the radiation-emitting surface of the diode laser (4) with the position ($M_{1,0}, M_{2,0}$) assumed by the centre of the intensity distribution of the radiation spot (V_1, V_2) formed on the relevant detector pair (18,19;20,21) if the scanning beam (b) is focussed on the information plane (2) in an optimum manner.
2. An apparatus as claimed in Claim 1, in which the composite diffraction element (9) is constituted by two subgratings (12, 13) characterized in that the sub-gratings (12,13) have a varying grating period (P_1, P_2) and in that the grating strips (14,16;15,17) are curved.
3. An apparatus as claimed in Claim 1 or 2 in which the diffraction element (9) is constituted by two sub-gratings (12,13) in which the grating strips (14,16) of the one sub-grating (12) have the same direction as those (15,17) of the other sub-grating (13) and the periods (P_1, P_2) of the sub-gratings are different, and in which the detector pairs (18,19;20,21) are juxtaposed in a direction parallel to the separating line (11) between the sub-gratings (12, 13), characterized in that the separating strips (22', 23') of the detector pairs extend at opposite angles (α_1, α_2) to the said connection line.
4. An apparatus as claimed in Claim 1 or 2 in which the diffraction element (9) is constituted by two sub-gratings (12, 13) which have the same grating period, whilst the grating strips (14,16) of the first sub-grating (12) extend at a



first angle and those (15,17) of the second sub-grating (13) extend at a second angle, which is equal but opposite to the first angle, to the separating line (11) of the two sub-gratings, and in which the detector pairs (18,19;20,21) are juxtaposed in a direction transversely to the direction of the said separating line (11), characterized in that the separating strips (22',23') of the detector pairs extend at equally large but opposite angles (β) to the said connection line.

Patentansprüche

1. Vorrichtung zum optischen Abtasten einer strahlungsreflektierenden Informationsebene (2), wobei die Vorrichtung einen ein Abtaststrahlenbündel (b) liefernden Diodenlaser (4) enthält, sowie ein Objektivsystem (6) zur Fokussierung des Abtaststrahlenbündels zur Bildung eines Abtastflecks (V) in der Informationsebene und zur Wiederabbildung des Abtastflecks auf ein zusammengesetztes, strahlungsempfindliches Detektionssystem (10) und ein zusammengesetztes, in dem Strahlungsweg zwischen dem Diodenlaser und dem Objektivsystem angeordnetes Beugungselement (9) zur Ablenkung des von der Informationsebene reflektierten Strahlungsbündels auf das strahlungsempfindliche Detektionssystem und zur Aufspaltung dieses Strahlungsbündels in eine Anzahl von Teilbündeln (b_1, b_2), die eine entsprechende Anzahl von Strahlungsflecken (V_1, V_2) auf einer entsprechenden Anzahl von Detektorpaaren (18, 19; 20, 21) des zusammengesetzten Detektionssystems (10) bilden, dadurch gekennzeichnet, daß für jedes Detektorpaar (18, 19; 20, 21) der Trennstreifen (22', 23') zwischen den beiden Detektoren mit der Linie, die den Mittelpunkt der strahlungsemitierenden Fläche des Diodenlasers (4) mit der, bei optimaler Fokussierung des Abtaststrahlenbündels (b_1) auf die Informationsebene (2), von dem Zentrum der Intensitätsverteilung des auf dem betreffenden Detektorpaar (18, 19; 20, 21) gebildeten Strahlungsflecks (V_1, V_2) angenommenen Lage ($M_{1,0}, M_{2,0}$) verbindet, einen spitzen Winkel ($\alpha_1, \alpha_2, \beta$) bildet.
2. Vorrichtung nach Anspruch 1, bei der das zusammengesetzte Beugungselement (9) von zwei Teilgittern (12, 13) gebildet wird, dadurch gekennzeichnet, daß die Teilgitter (12, 13) eine variierende Gitterperiode (P_1, P_2) haben und daß die Gitterstreifen (14, 16; 15, 17) gekrümmt sind.

3. Vorrichtung nach Anspruch 1 oder 2, bei der das Beugungselement (9) aus zwei Teilgittern (12, 13) zusammengesetzt ist, in denen die Gitterstreifen (14, 16) des einen Teilgitters (12) die gleiche Richtung wie die (15, 17) des anderen Teilgitters (13) haben und die Gitterperioden (P_1, P_2) der Teilgitter unterschiedlich sind, und bei der die Detektorpaare (18, 19; 20, 21) in einer parallel zu der Trennlinie (11) zwischen den Teilgittern (12, 13) liegenden Richtung nebeneinanderliegen, dadurch gekennzeichnet, daß die Trennstreifen (22', 23') der Detektorpaare mit der genannten Verbindungslinie entgegengesetzte Winkel (α_1, α_2) bilden.
4. Vorrichtung nach Anspruch 1 oder 2, bei der das Beugungselement (9) aus zwei Teilgittern (12, 13) mit gleicher Gitterperiode zusammengesetzt ist, während die Gitterstreifen (14, 16) des ersten Teilgitters (12) mit der Trennlinie (11) zwischen den Teilgittern (12, 13) einen ersten Winkel bilden und die (15, 17) des zweiten Teilgitters (13) mit der genannten Trennlinie einen zweiten Winkel bilden, der gleich, aber entgegengesetzt dem ersten Winkel ist, und bei der die Detektorpaare (18, 19; 20, 21) in einer quer zu der Richtung der genannten Trennlinie (11) liegenden Richtung nebeneinanderliegen, dadurch gekennzeichnet, daß die Trennstreifen (22', 23') der Detektorpaare mit der genannten Verbindungslinie gleich große, aber entgegengesetzte Winkel (β) bilden.

Revendications

1. Dispositif pour le balayage optique d'un plan d'information réfléchissant le rayonnement (2), comportant une diode laser (4) fournissant un faisceau de balayage (b), un système d'objectif (6) pour focaliser le faisceau de balayage de manière à constituer un spot de balayage V dans le plan d'information et pour représenter le spot de balayage sur un système de détection composé sensible au rayonnement (10), et un élément de diffraction composé (9) disposé dans le trajet de rayonnement entre la diode laser et le système d'objectif pour dévier le faisceau de rayonnement réfléchi par le plan d'information vers le système de détection sensible au rayonnement et pour diviser ledit faisceau en une pluralité de sous-faisceaux (b_1, b_2) formant une pluralité de spots de rayonnement correspondants (V_1, V_2) sur une pluralité de paires de détecteurs correspondants (18, 19; 20, 21) du système de détection composé (10), caractérisé en ce que, pour



chaque paire de détecteurs (18, 19; 20, 21), la bande de séparation (22', 23') située entre les deux détecteurs fait un angle aigu (α_1 , α_2 , β) avec la ligne reliant le centre de la surface d'émission de rayonnement de la diode laser (41) à la position ($M_{1,0}$, $M_{2,0}$) occupée par le centre de la répartition d'intensité du spot de rayonnement (V_1 , V_2) formé sur la paire de détecteurs concernée (18, 19; 20, 21) si le faisceau de balayage (b_1) est focalisé optimalement sur le plan d'information (2).

2. Dispositif selon la revendication 1, dans lequel l'élément de diffraction composé (9) est constitué par deux sous-réseaux (12, 13), caractérisé en ce que les sous-réseaux (12, 13) présentent une période de réseau variable (p_1 , p_2) et en ce que les bandes de réseau (14, 16; 15, 17) sont courbées.
3. Dispositif selon la revendication 1 ou 2, dans lequel l'élément de diffraction (9) est constitué par deux sous-réseaux (12, 13), dans lequel les bandes de réseau (14, 16) de l'un des deux sous-réseaux (12) présentent la même direction que celles (15, 17) de l'autre sous-réseau (13) et les périodes de réseau (p_1 , p_2) des sous-réseaux sont différentes, et dans lequel les paires de détecteurs (18, 19; 20, 21) sont juxtaposées dans une direction parallèle à la ligne de séparation (11) entre les sous-réseaux (12, 13), caractérisé en ce que les bandes de séparation (22', 23') des paires de détecteurs font des angles opposés (α_1 , α_2) avec ladite ligne de connexion.
4. Dispositif selon la revendication 1 ou 2, dans lequel l'élément de diffraction (9) est constitué par deux sous-réseaux (12, 13) présentant la même période de réseau, alors que les bandes de réseau (14, 16) du premier sous-réseau (12) font un premier angle avec la ligne de séparation des deux sous-réseaux et que les bandes de réseau (15, 17) du deuxième sous-réseau (13) font un deuxième angle, qui est égal mais opposé au premier angle, avec ladite ligne de séparation des deux sous-réseaux, et dans lequel les paires de détecteurs (18, 19; 20, 21) sont juxtaposées dans une direction s'étendant transversalement à la direction de ladite ligne de séparation (11), caractérisé en ce que les bandes de séparation (22', 23') des paires de détecteurs font des angles également élevés mais opposés à ladite ligne de connexion.